


<b>Search Notes</b> 	<b>Application/Control No.</b> 10580456	<b>Applicant(s)/Patent Under Reexamination</b> YASUDA ET AL.
	<b>Examiner</b> Haidung D Nguyen	<b>Art Unit</b> 1796

SEARCHED			
Class	Subclass	Date	Examiner
252	182.11	10/22/08	\HN\

SEARCH NOTES		
Search Notes	Date	Examiner
inventor search in eDan and Palm	10/24/08	\HN\

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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